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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 4 sheets

Complete if Known

Application Number	10/028,198
Filing Date	12/20/2001
First Named Inventor	Chung J. Lee
Group Art Unit	1773
Examiner Name	ZACHARIA
Attorney Docket Number	108324.0005 DIEL-0004

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U.S. PATENT DOCUMENTS

Examiner Initials *	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
REZ	1	SN 09/925,712	08/09/2001	Lee	Entire Content
REZ	2	US 3,268,599	08/23/1966	Chow	Entire Content
REZ	3	US 3,274,267	09/20/1966	Chow	Entire Content
REZ	4	US 3,280,202	10/18/1966	Gilch	Entire Content
REZ	5	US 3,288,728	11/29/1966	Gorham	Entire Content
REZ	6	US 3,332,891	07/25/1967	Chow et al.	Entire Content
REZ	7	US 3,342,754	09/19/1997	Gorham, et al.	Entire Content
REZ	8	US 3,349,045	10/24/1967	Gilch	Entire Content
REZ	9	US 3,379,803	04/23/1968	Tittmann, et al.	Entire Content
REZ	10	US 3,503,903	03/31/1970	Shaw, et al.	Entire Content
REZ	11	US 3,509,075	04/28/1970	Niegish et al.	Entire Content
REZ	12	US 3,626,032	12/07/1971	Norris	Entire Content
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REZ	14	US 3,940,530	02/24/1976	Loeb et al.	Entire Content
REZ	15	US 5,268,202	12/07/1993	You, et al.	Entire Content
REZ	16	US 5,538,758	07/23/1996	Beach, et al.	Entire Content
REZ	17	US 5,879,808	03/09/1999	Wary, et al.	Entire Content
REZ	18	US 5,958,510	09/28/1999	Sivaramakrishnam,	Entire Content
REZ	19	US 6,130,171	10/10/2000	Gomi	Entire Content
REZ	20	US 6,140,456	10/31/2000	Foggiator	Entire Content
REZ	21	US 6,265,320	07/24/2001	Shi, et al.	Entire Content

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Examiner Initials *	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)				
REZ	22	EP 0 349 032 A2	01/03/1990	Van der Werff,		
REZ	23	EP 0 523 479 A2	01/20/1993	Lawrence, et al.		
REZ	24	EP 0 856 503 A1	08/05/1998	Maruyama, et al.		
REZ	25	GB 650 947	03/07/1951	Szwarc		

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Signature

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Sheet	2	of	4 sheets
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Application Number	10/028,198	
Filing Date	12/20/2001	REC
First Named Inventor	Chung J. Lee	
Group Art Unit	1702 1773	MAY 1
Examiner Name	Ramsey E. Zacharia	
Attorney Docket Number	108324.0005 DIEL-0004	TC

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U.S. PATENT DOCUMENTS

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		Country Code ³ - Number ⁴ - Kind Code ⁵ (<i>if known</i>)				
REZ	26	GB 673 651	06/11/1952	Szwarc		
REZ	27	WO 97/15699	05/01/1997	Beach, et al.		
REZ	28	WO 97/42356	11/13/1997	Gleason et al.		
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REZ	30	WO-97/15951	05/01/1997	Wary et al.		
REZ	31	WO-99/21705	05/06/1999	Lee et al.		
REZ	32	WO-99/21706	05/06/1999	Lee et al.		
REZ	33	WO-99/21924	05/06/1999	Lee et al.		

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Sheet 3 of 4 sheets

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Application Number	10/028,198
Filing Date	12/20/2001
First Named Inventor	Chung J. Lee
Group Art Unit	1702-1773
Examiner Name	Ramsey E. Zacharia
Attorney Docket Number	108324.0005 DIEL-0004

RECEIVED**MAY 13 2003****TC 1700****OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS**

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
REF	34	BRUN A.E. 100NM: THE UNDISCOVERED COUNTRY, SEMICONDUCTOR INTERNATIONAL, P79, FEB. 2000	
REF	35	CHOW, S. W., et al., "The synthesis of 1,1,2,2,9,9,10,10-octafluorou2, 2Paracyclophane" Journal of Organic Chemistry, American Chemical Society. Easton, US Vol 35(1), 1970 pages 20-22. 1-1970	
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REF	42	LANG, C-I, "Vapor Deposition of Very low k Polymer Films, Poly (Naphthalene), Poly (Fluorinated Naphthalene)" Materials Research Society Symposium Proceedings, Materials Research Society, Pittsburgh, PA US, Vol. 381, 17 April 1995 (1995-04-17), pgs. 45-50	
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Application Number 10/028,198

Filing Date 12/20/2001

First Named Inventor Chung J. Lee

Group Art Unit 1702 (773)

Examiner Name Ramsey E. Zacharia

Attorney Docket Number 108324.0005 DIEL-0004

RECEIVED**MAY 13 2003****TC 1700****OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS**

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
REF	46	MORGEN, M., et al., "Morphological Transitions in Fluorinated and Non-Fluorinated Parylenes," Material Research Society Symposium Proceedings, Vol. 565, 1999, pgs. 297-302 1-1999	
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